



03N50-CD

Preliminary

Power MOSFET

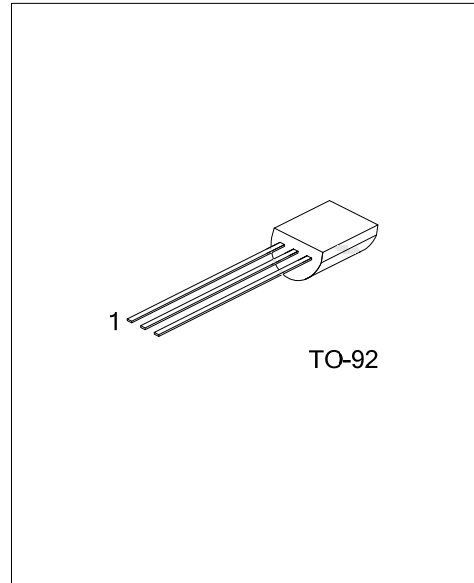
0.3A, 500V N-CHANNEL POWER MOSFET

DESCRIPTION

The UTC **03N50-CD** is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(on)} \leq 27 \Omega @ V_{GS}=10V, I_D=0.15A$
- * High breakdown voltage



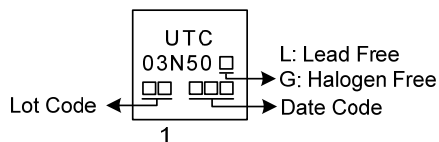
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
03N50L-T92-B	03N50G-T92-B	TO-92	G	D	S	Tape Box
03N50L-T92-K	03N50G-T92-K	TO-92	G	D	S	Bulk

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>03N50G-T92-B</p> <p>(1)Packing Type (2)Package Type (3)Green Package</p>	<p>(1) B: Tape Box, K: Bulk (2) T92: TO-92 (3) G: Halogen Free and Lead Free, L: Lead Free</p>
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous	I_D	0.3	A
	Pulsed	I_{DM}	0.6	A
Power Dissipation		P_D	425	mW
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating : Pulse width limited by maximum junction temperature.

■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient		θ_{JA}	416	$^\circ\text{C/W}$
Junction to Case		θ_{JC}	294	$^\circ\text{C/W}$

Note: Device mounted on FR-4 substrate P_C board, 2oz copper, with 1inch square copper plate.

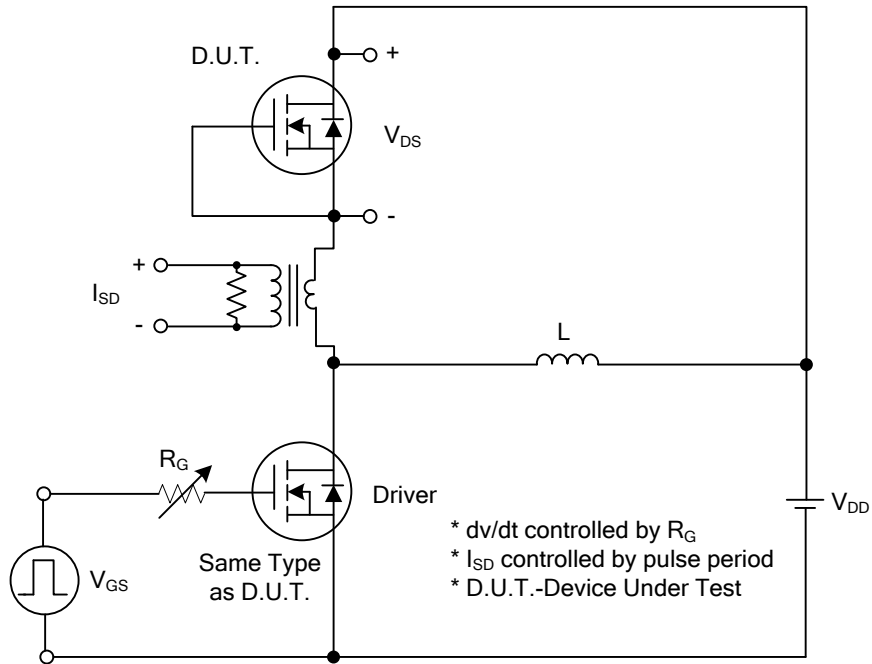
■ ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV_{DSS}	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	500			V	
Drain-Source Leakage Current		I_{DSS}	$V_{DS}=500\text{V}, V_{GS}=0\text{V}, T_A=25^\circ\text{C}$			10	μA	
Gate-Source Leakage Current	Forward	I_{GSS}	$V_{GS}=+30\text{V}, V_{DS}=0\text{V}$			+100	nA	
	Reverse		$V_{GS}=-30\text{V}, V_{DS}=0\text{V}$			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.0		4.0	V	
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	$V_{GS}=10\text{V}, I_D=0.15\text{A}$			27	Ω	
DYNAMIC PARAMETERS								
Input Capacitance		C_{ISS}	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1.0\text{MHz}$		30		pF	
Output Capacitance		C_{OSS}				3.5		pF
Reverse Transfer Capacitance		C_{RSS}				0.2		pF
SWITCHING PARAMETERS								
Total Gate Charge		Q_G	$V_{DS}=400\text{V}, V_{GS}=10\text{V}, I_D=0.3\text{A}, I_D=100\mu\text{A}$ (Note1,2)		7		nC	
Gate to Source Charge		Q_{GS}				3		nC
Gate to Drain Charge		Q_{GD}				0.8		nC
Turn-ON Delay Time		$t_{D(ON)}$	$V_{DS}=100\text{V}, V_{GS}=10\text{V}, I_D=0.3\text{A}, R_G=25\Omega$ (Note1,2)		6		ns	
Rise Time		t_R				16		ns
Turn-OFF Delay Time		$t_{D(OFF)}$				20		ns
Fall-Time		t_F				105		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current		I_S				0.3	A	
Maximum Body-Diode Pulsed Current		I_{SM}				0.6	A	
Drain-Source Diode Forward Voltage		V_{SD}	$I_S=0.3\text{A}, V_{GS}=0\text{V}$			1.4	V	
Reverse Recovery Time		t_{rr}	$V_{GS}=0\text{V}, I_S=0.3\text{A}, di/dt=100\text{A}/\mu\text{s}$		72		ns	
Reverse Recovery Charge		Q_{rr}				160		nC

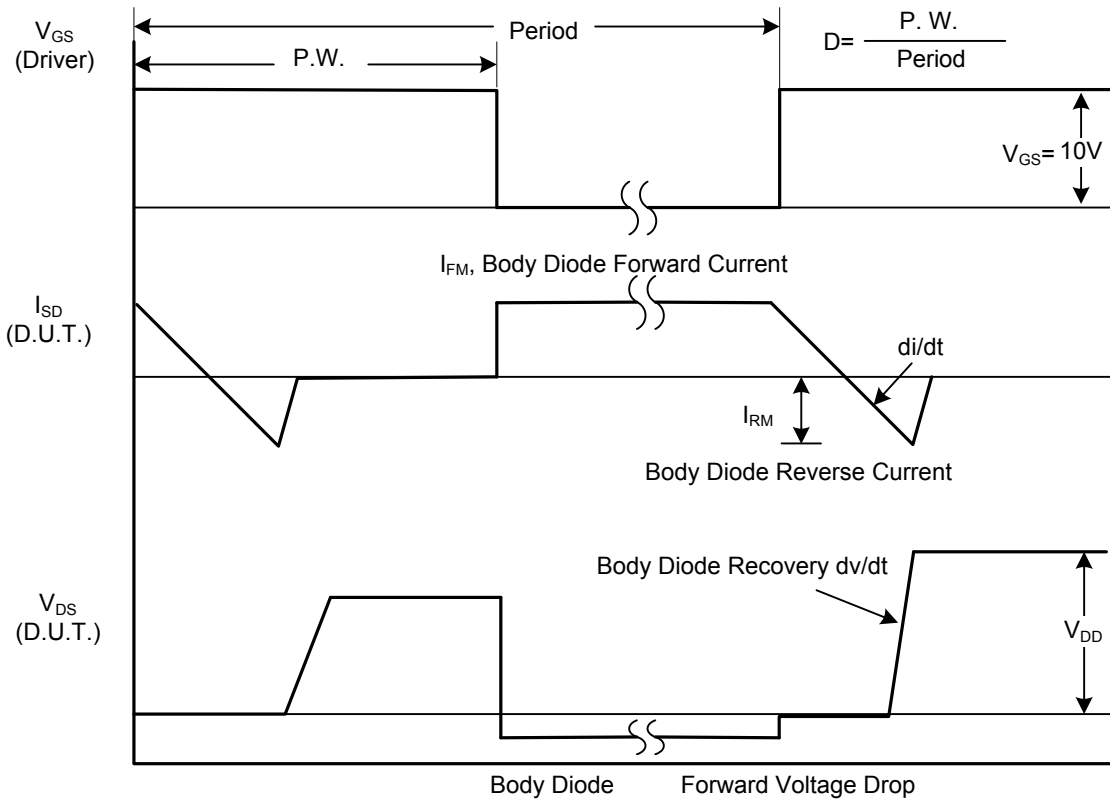
Notes: 1. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

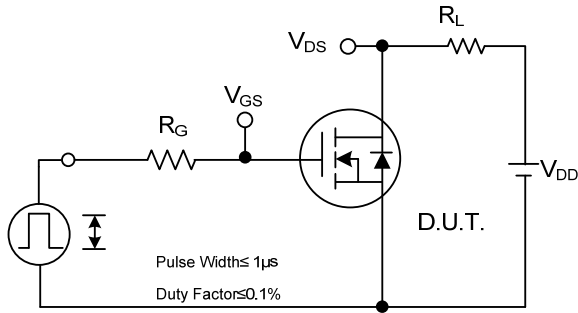


Peak Diode Recovery dv/dt Test Circuit

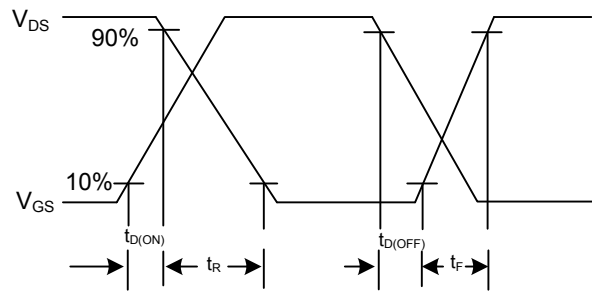


Peak Diode Recovery dv/dt Waveforms

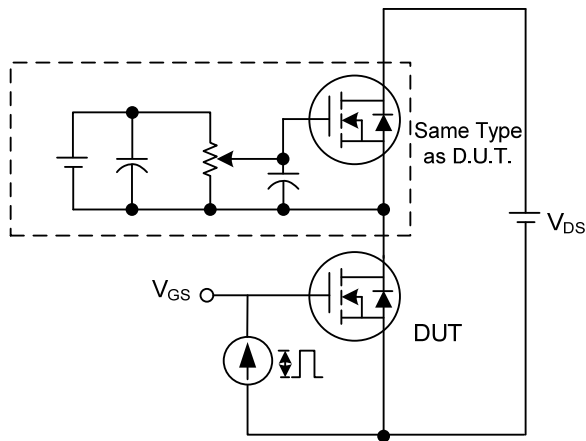
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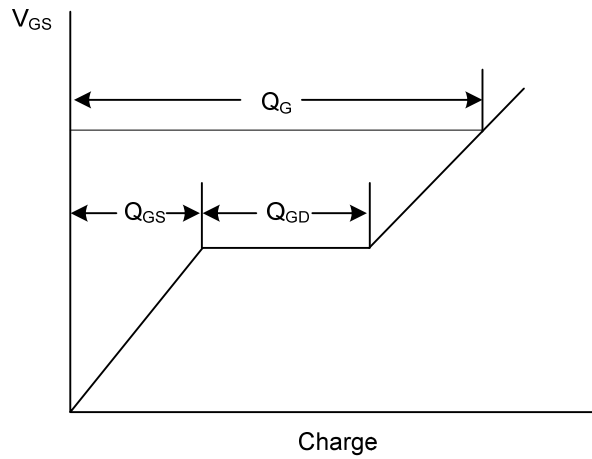
Switching Test Circuit



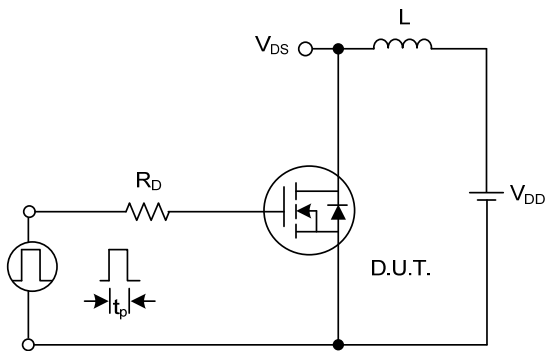
Switching Waveforms



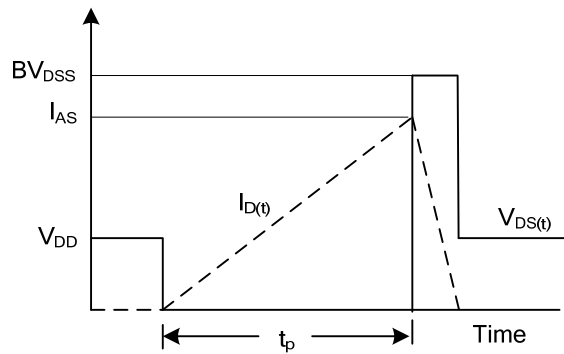
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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